

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination DE HAEN ET AL.	
		Examiner Brandon J. Fetterolf, PhD	Art Unit 1642	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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*	N	WO 200256907 A2	07-2002	World Intellect	BACHMANN et al.	
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NON-PATENT DOCUMENTS

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